Notice of References Cited Application/Control No. 10/519,339 Examiner Khanh T. Nguyen Applicant(s)/Patent Under Reexamination MIYAGAWA ET AL. Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,110,669	05-1992	Knobel et al.	428/215
*	В	US-6,671,165	12-2003	Nakazawa et al.	361/502
*	С	US-6,654,229	11-2003	Yanagisawa et al.	361/502
*	D	US-6,392,867	05-2002	Yamada et al.	361/502
*	Е	US-5,706,165	01-1998	Saito et al.	361/502
*	F	US-6,241,057	06-2001	Hiatt, Anthony R.	188/219.1
*	G	US-7,224,574	05-2007	Fujino et al.	361/502
*	Н	US-6,773,466	08-2004	Hiratsuka et al.	29/25.03
*	ı	US-6,522,523	02-2003	Takatomi et al.	361/502
*	J	US-5,682,288	10-1997	Wani, Takayuki	361/502
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2005-238534	09-2005	Japan-Abstract	Miyagawa et al.	B32B 9/00
	0	JP 02-008052	01-1990	Japan-Abstract	Fujii et al.	B32B 27/36
	Р	JP 2000-012388	01-2000	Japan	Miyamoto, Tomoharu	H01G 9/16
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
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	w							
	x							

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.